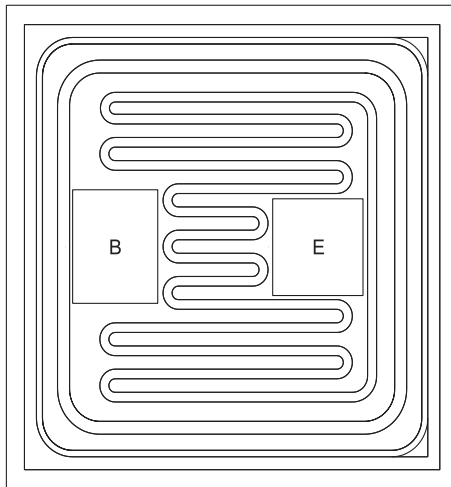


**PROCESS DETAILS**

Process	EPITAXIAL PLANAR
Die Size	26 x 26 MILS
Die Thickness	9.0 MILS
Base Bonding Pad Area	6.1 x 4.9 MILS
Emitter Bonding Pad Area	5.2 x 5.2 MILS
Top Side Metalization	Al - 30,000Å
Back Side Metalization	Au - 18,000Å

**GEOMETRY**



BACKSIDE COLLECTOR

R1

**GROSS DIE PER 4 INCH WAFER**

16,880

**PRINCIPAL DEVICE TYPES**

CMPT6520  
CMPTA92  
CXTA92  
CZTA92  
MPSA92

145 Adams Avenue  
Hauppauge, NY 11788 USA  
Tel: (631) 435-1110  
Fax: (631) 435-1824  
www.centalsemi.com

R1 (27- November 2001)